

<b>Notice of References Cited</b>	Application/Control No. 10/526,315	Applicant(s)/Patent Under Reexamination VAN WAGENINGEN ET AL.	
	Examiner Jeffrey M. Rutkowski	Art Unit 2619	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code,	Date MM-YYYY	Name	Classification
*	A	US-7,248,583	07-2007	Van Wageningen et al.	370/392
*	B	US-2003/0012210	01-2003	Van Wageningen et al.	370/419
*	C	US-2003/0152082	08-2003	Van Wageningen et al.	370/395.4
*	D	US-2003/0095558	05-2003	Chung et al.	370/417
*	E	US-2003/0072312	04-2003	Alasti et al.	370/395.4
*	F	US-2003/0227932	12-2003	Meempat et al.	370/415
*	G	US-7,068,672	06-2006	Jones, James W.	370/412
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.